



# National Accreditation Board for Testing and Calibration Laboratories

## SCOPE OF ACCREDITATION

Laboratory Name MITSUI CHEMICALS INDIA PVT. LTD. (SOLAR PV LAB), PLOT 5 AND 6, SWASTIK INDUSTRIAL ESTATE, AHMEDABAD, GUJARAT, INDIA

Accreditation Standard ISO/IEC 17025:2017

Certificate Number TC-8906 Page No. : 1 / 19

Validity 01/04/2020 to 31/03/2022 Last Amended on -

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
<b>Permanent Facility</b>				
1	ELECTRONICS-ELECTRONIC COMPONENTS & EQUIPMENT SUB ASSEMBLIES	Conduits of Junction Box in Solar Photovoltaic Module { Dimensions: upto 2.1 m (L) x 1.3 m (B) and power upto 600W }	Conduit Bending Test	IS 61730 (Part 2) [Clause No: 11.3 /MST 33]: 2004
2	ELECTRONICS-ELECTRONIC COMPONENTS & EQUIPMENT SUB ASSEMBLIES	Junction Box of Solar Photovoltaic Module { Dimensions: upto 2.1 m (L) x 1.3 m (B) and power upto 600W }	Terminal Box Knockout Test	IS 61730 (Part 2) [Clause No: 11.3/ MST 44]: 2004
3	ELECTRONICS-ELECTRONIC COMPONENTS & EQUIPMENT SUB ASSEMBLIES	Solar Photovoltaic Module { Dimensions: upto 2.1 m (L) x 1.3 m (B) and power upto 600W }	Partial Discharge Test	IS 61730 (Part 1) (Clause No:5.4.4) & IS 61730 (Part 2)(Clause No: 11.1): 2004
4	ELECTRONICS-ELECTRONIC COMPONENTS & EQUIPMENT SUB ASSEMBLIES	Solar Photovoltaic Module (Crystalline(c-Si), Amorphous Silicon(a-Si), Cadmium Telluride(CdTe), Cu (In,GA) (S,Se) <sup>2</sup> ) { Dimensions: upto 2.1 m (L) x 1.3 m (B) and power upto 600W }	Damp Heat Test	IEC 61215 (Part 1 & Part 2) [ Clause No: 4.13/ MQT 13] & IEC 61215 (Part1 & Sub Parts 1 to 4) (Clause No: 11.13) & IEC 61730 (Part 2) [Clause No: 10.30/MST 53]:
5	ELECTRONICS-ELECTRONIC COMPONENTS & EQUIPMENT SUB ASSEMBLIES	Solar Photovoltaic Module (Crystalline(c-Si), Amorphous Silicon(a-Si), Cadmium Telluride(CdTe), Cu (In,GA) (S,Se) <sup>2</sup> )	Bypass Diode Functionality Test	IEC 61215 (Part 1 & Part 2) [Clause No: 4.18.2 / MQT 18.2] & IEC 61215(Part 1 & Sub Parts 1 to 4) (Clause No: 11.18): 2016